

Search Notes**Application/Control No.**

10/698,222

Examiner

Toan M. Le

Applicant(s)/Patent under Reexamination

SHI ET AL.

Art Unit

2863

SEARCHED

Class	Subclass	Date	Examiner
702	57	3/24/2005	TL
324	671	3/24/2005	TL
324	455	3/24/2005	TL
438	17	3/24/2005	TL
438	16	3/24/2005	TL
324	765	3/24/2005	TL
Above	Updated	9/26/2005	TL

INTERFERENCE SEARCHED

Class	Subclass	Date	Examiner
702	57	9/27/2005	TL
438	17	9/27/2005	TL

**SEARCH NOTES
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
Contactless Insulating Dielectric Film Characterization	3/23/2005	TL
Substrate, Dielectric Film, Voltage, Kelvin Probe	3/23/2005	TL
Substrate, Film, Thickness, Nitrogen, Charge, Non-Contact	3/18/2005	TL
Insulating Film, Surface Voltage, Charge, Deposition, Average	9/26/2005	TL
East-See Search History Printout	9/26/2005	TL
ScienceDirect, IEEE Xplore	9/26/2005	TL